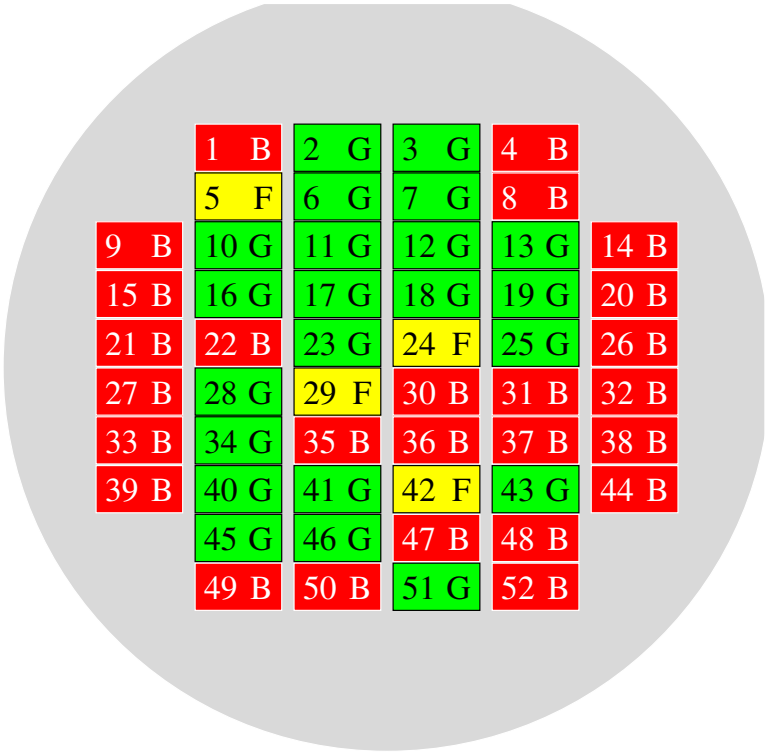
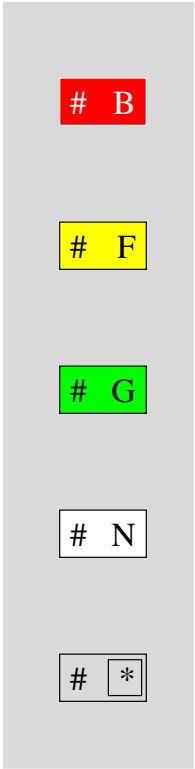
Die quality map for wafer 130 s/n: 21316-05-04

Date: 02/26/99